

1. Features

- $R_{DS(ON)}=2.1\text{m}\Omega(\text{typ.}) @ V_{GS}=10\text{V}$
- Very Low On-resistance $R_{DS(ON)}$
- Low C_{RSS}
- Fast switching
- 100% avalanche tested
- Improved dv/dt capability

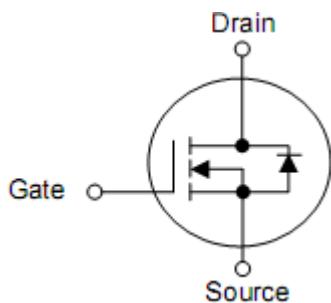
2. Applications

- PWM Application
- Power Management
- Load switch

3. Symbol



TO-252



Pin	Function
1	Gate
2	Drain
3	Source

4. Ordering Information

Part Number	Package	Brand
KND2803S	TO-252	KIA

5. Absolute maximum ratings

$T_C=25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Rating	Units
Drain-source voltage	V_{DSS}	30	V
Continuous drain current	I_D	150	A
	I_D	82	A
Pulsed drain current -Pulsed ¹⁾	I_{DM}	360	A
Gate-source voltage	V_{GS}	± 20	V
Single pulse avalanche energy ²⁾	E_{AS}	480	mJ
Power dissipation($T_C=25^\circ\text{C}$)	P_D	48	W
Operating junction and storage temperature range	T_J, T_{STG}	-55 to 150	$^\circ\text{C}$
Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds	T_L	300	$^\circ\text{C}$

*Drain current limited by maximum junction temperature.

6. Thermal characteristics

Parameter	Symbol	Rating	Unit
Thermal resistance junction-case	$R_{\theta JC}$	2.6	$^\circ\text{C}/\text{W}$

7. Electrical characteristics

($T_C=25^\circ\text{C}$ unless otherwise noted)

Parameter	Symbol	Test Conditions	Min	Typ	Max	Units
Drain-source breakdown voltage	BV_{DSS}	$V_{\text{GS}}=0\text{V}, I_{\text{D}}=250\mu\text{A}$	30	-	-	V
Drain-source leakage current	I_{DSS}	$V_{\text{DS}}=30\text{V}, V_{\text{GS}}=0\text{V}$	-	-	1	μA
		$V_{\text{DS}}=24\text{V}, T_C=125^\circ\text{C}$	-	-	50	μA
Gate-source forward leakage	I_{GSS}	$V_{\text{GS}}=\pm 20\text{V}, V_{\text{DS}}=0\text{V}$	-	-	± 100	nA
Gate threshold voltage	$V_{\text{GS(TH)}}$	$V_{\text{DS}}=V_{\text{GS}}, I_{\text{D}}=250\mu\text{A}$	1.0	1.6	2.2	V
Drain-source on-resistance	$R_{\text{DS(on)}}$	$V_{\text{GS}}=10\text{V}, I_{\text{D}}=20\text{A}$	-	2.1	2.8	$\text{m}\Omega$
		$V_{\text{GS}}=4.5\text{V}, I_{\text{D}}=10\text{A}$	-	2.8	3.8	$\text{m}\Omega$
Input capacitance	C_{iss}	$V_{\text{DS}}=25\text{V}, V_{\text{GS}}=0\text{V}$ $f=1\text{MHz}$	-	5705	-	pF
Output capacitance	C_{oss}		-	530	-	pF
Reverse transfer capacitance	C_{rss}		-	500	-	pF
Turn-on delay time	$t_{\text{d(on)}}$	$V_{\text{GS}}=10\text{V}, V_{\text{DS}}=15\text{V},$ $R_L=3.3\Omega, I_{\text{D}}=30\text{A}$ ³⁾	-	12	-	ns
Rise time	t_r		-	15	-	ns
Turn-off delay time	$t_{\text{d(off)}}$		-	78	-	ns
Fall time	t_f		-	30	-	ns
Total gate charge(10V)	Q_g	$V_{\text{DS}}=15\text{V}, I_{\text{D}}=40\text{A}$ $V_{\text{GS}}=10\text{V}$ ³⁾	-	112	-	nC
Gate-source charge	Q_{gs}		-	25	-	nC
Gate-drain charge	Q_{gd}		-	28	-	nC
Maximum Continuous Drain-Source Diode Forward Current	I_s	—	-	-	140	A
Maximum Pulsed Drain-Source Diode Forward Current	I_{SM}	—	-	-	360	A
Drain to Source Diode Forward Voltage	V_{SD}	$V_{\text{GS}}=0\text{V}, I_{\text{SD}}=20\text{A},$ $T_J=25^\circ\text{C}$	-	-	1.2	VS
Body Diode Reverse Recovery Time	t_{rr}	$I_F=30\text{A}, dI/dt=100\text{A}/\mu\text{s}$	-	-	22	nS
Body Diode Reverse Recovery Charge	Q_{rr}		-	-	13	nC

Note:

- 1) Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature
- 2) EAS condition: $T_J=25^\circ\text{C}, V_{\text{DD}}=20\text{V}, V_{\text{G}}=10\text{V}, R_{\text{G}}=25\Omega, L=0.5\text{mH}$.
- 3) Pulse Test: Pulse Width $\leq 300\text{us}$, Duty Cycle $\leq 0.5\%$

8. Typical operating characteristics

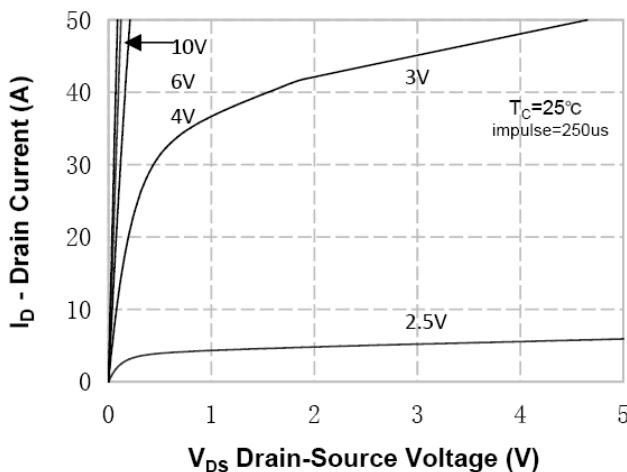


Figure 1. On-Region Characteristics

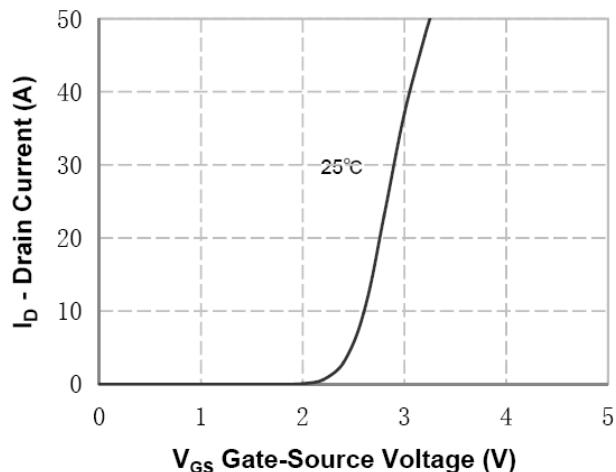


Figure 2. Transfer Characteristics

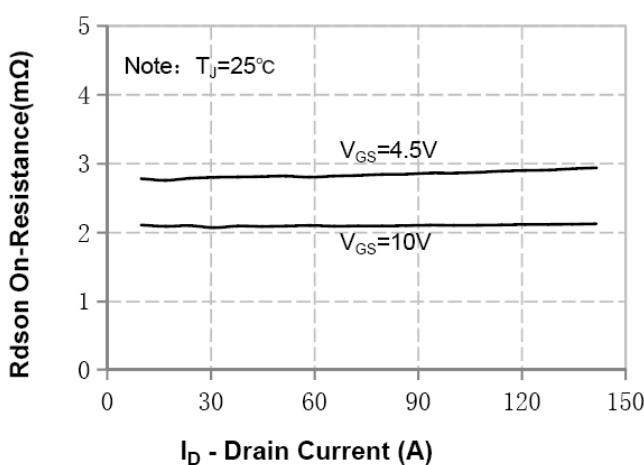


Figure 3. On-Resistance Variation vs
Drain Current and Gate Voltage

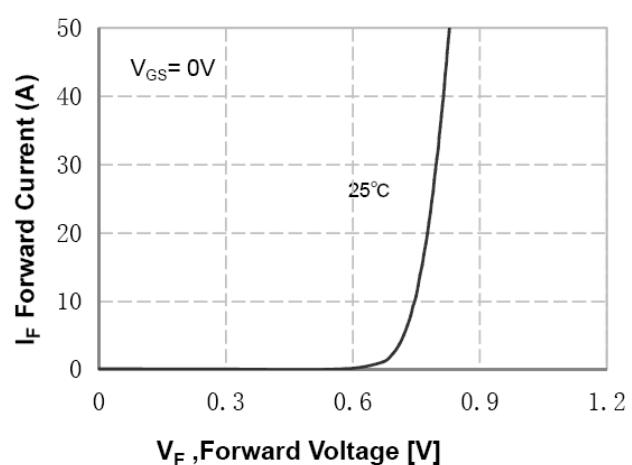


Figure 4. Body Diode Forward Voltage
Variation vs Source Current

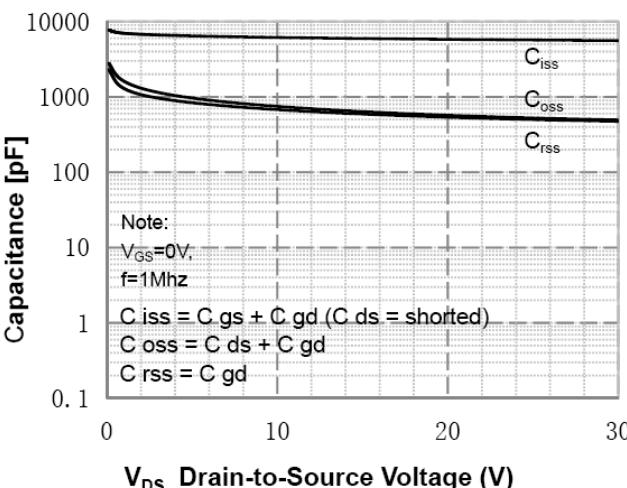


Figure 5. Capacitance Characteristics

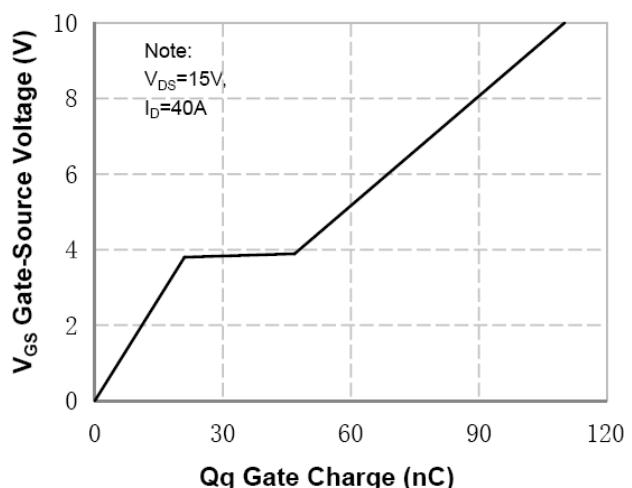


Figure 6. Gate Charge Characteristics

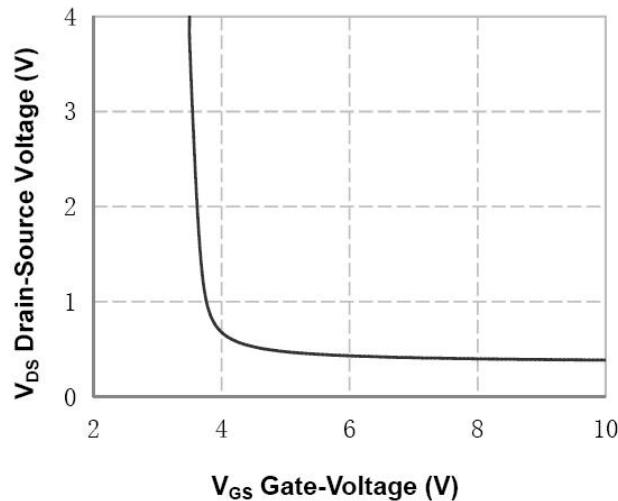


Figure 7. V_{DS} Drain-Source Voltage vs Gate Voltage

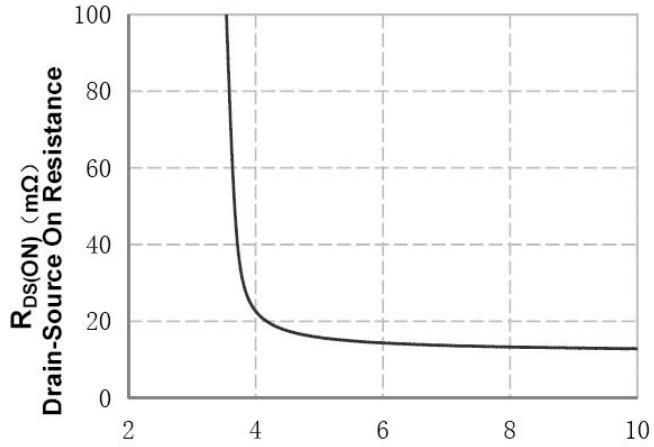


Figure 8. On-Resistance vs Gate Voltage

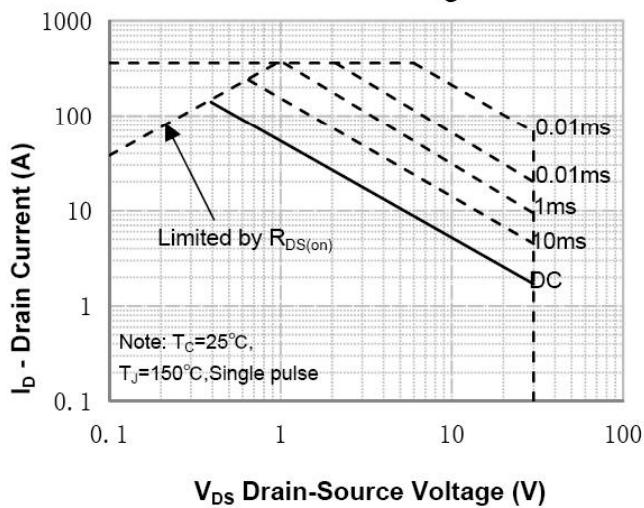


Figure 9. Maximum Safe Operating Area

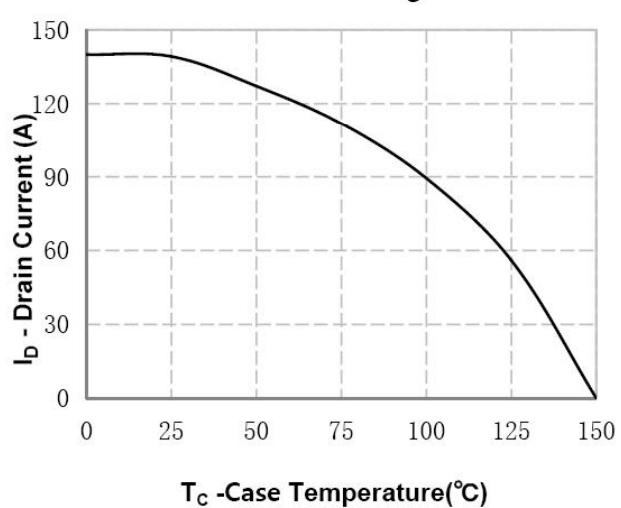


Figure 10. Maximum Continuous Drain Current vs Case Temperature

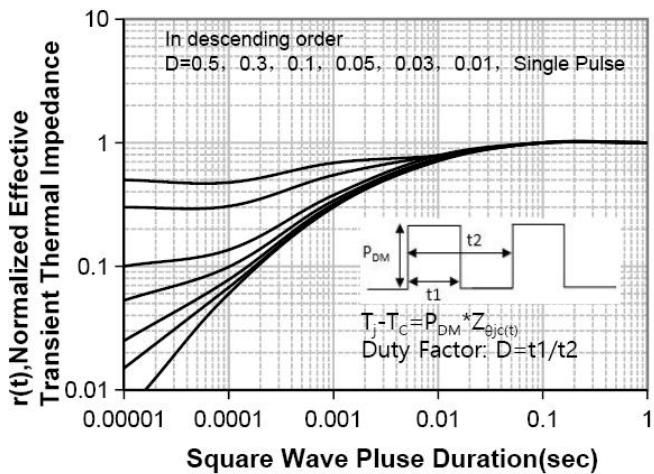
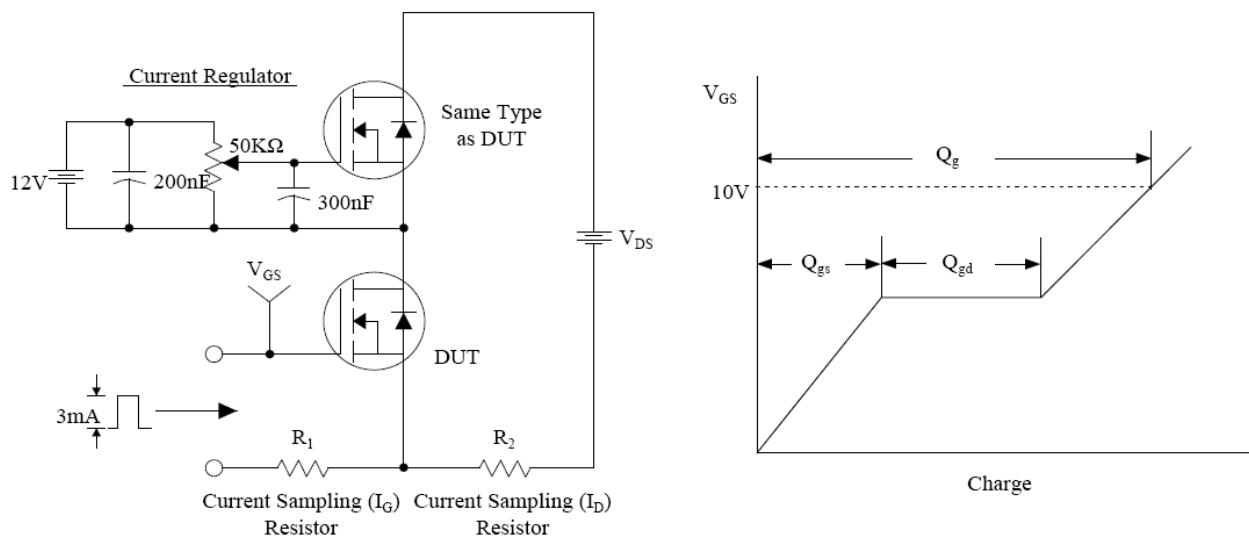


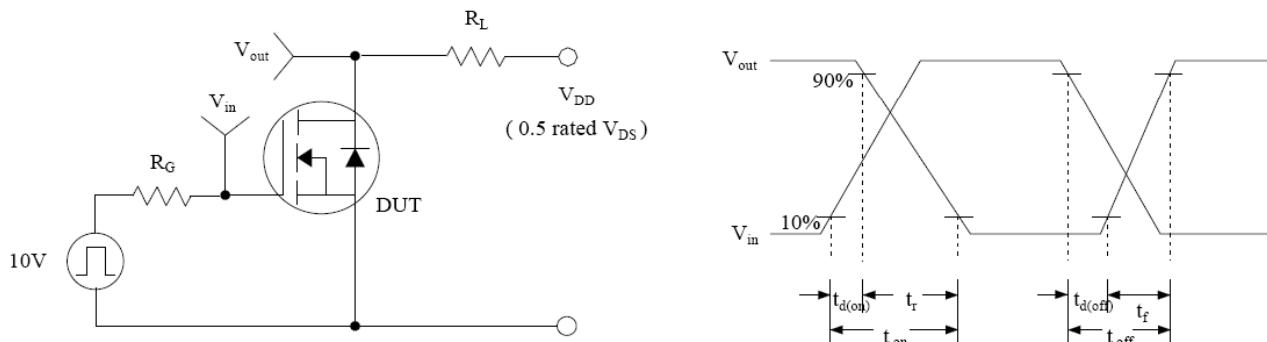
Figure 11. Transient Thermal Response Curve

9. Test Circuits and Waveforms

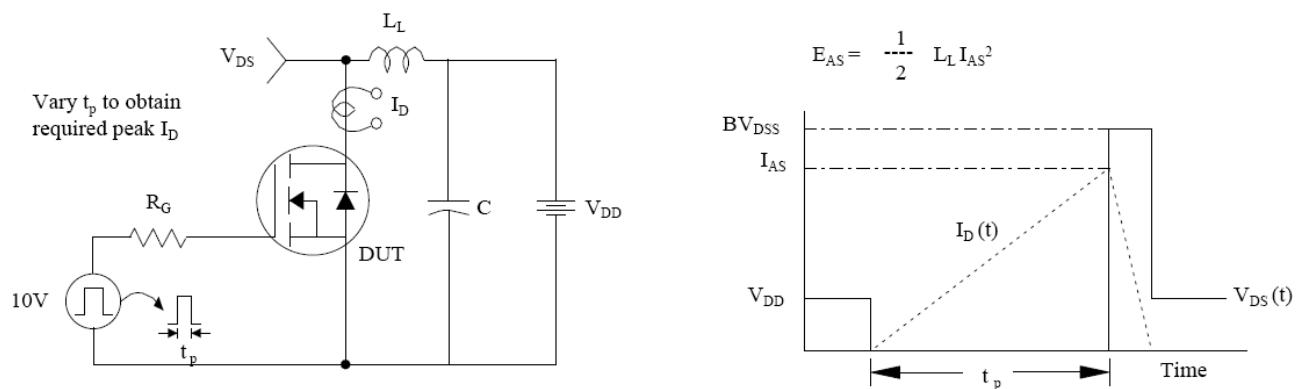
Gate Charge Test Circuit & Waveform



Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching Test Circuit & Waveforms



Peak Diode Recovery dv/dt Test Circuit & Waveforms

